

Fig.4 Snapback characteristics in pMOS.

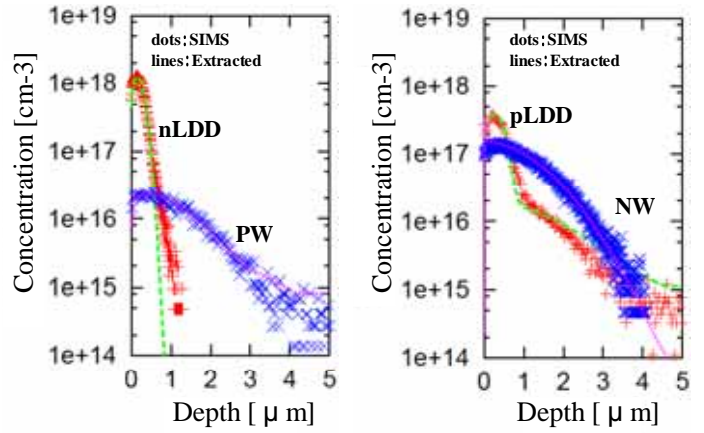
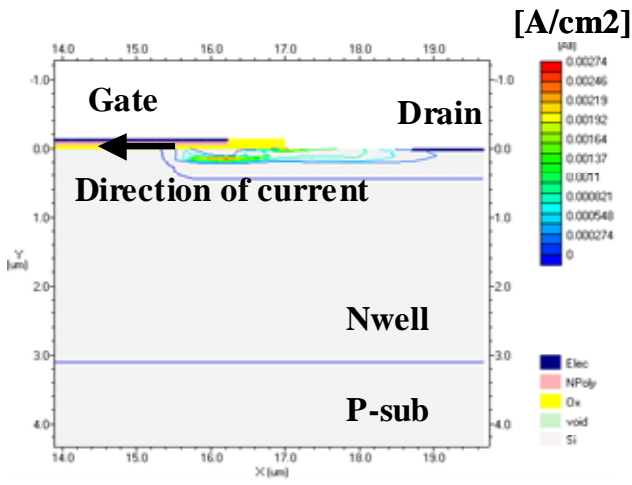


Fig.6 Impurity profiles extracted from SIMS.



(a) Region A

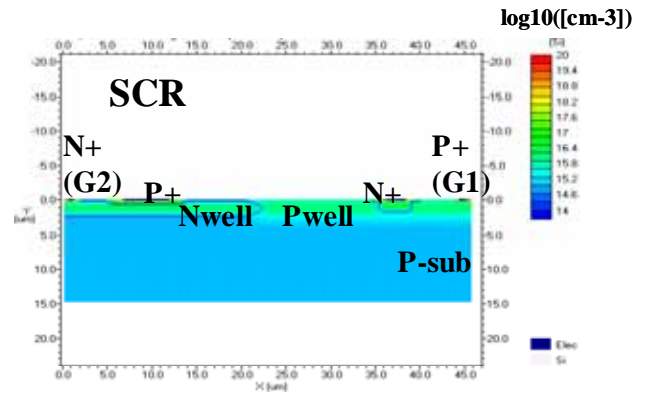
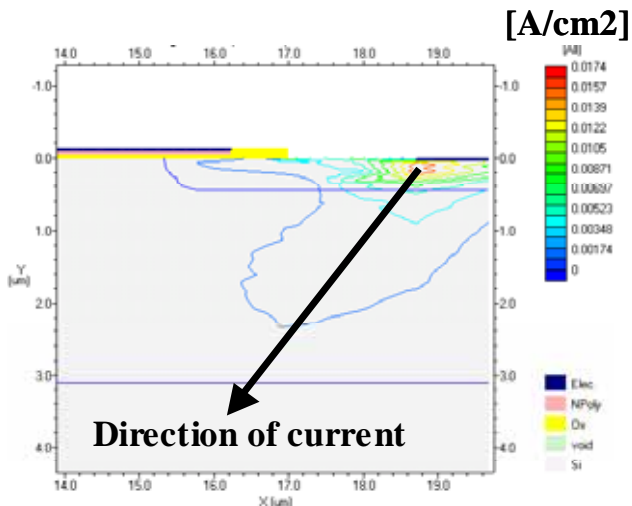


Fig.7 2D impurity profile of SCR.



(b) Region B

Fig.5 Distribution of hole current density.

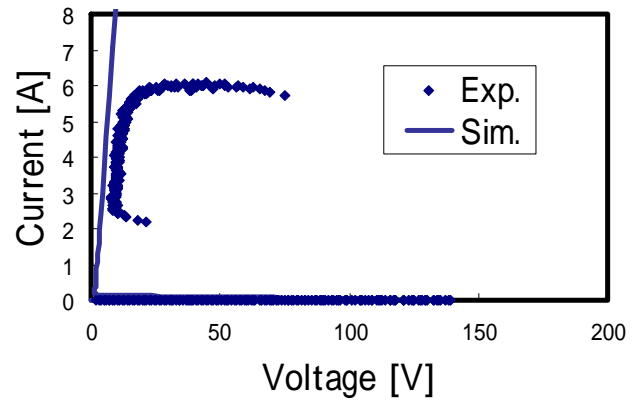


Fig.8 Comparison between TLP measurement and simulation in SCR.



